

**Search Notes**

Application/Control No.

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Examiner

Hai H. Huynh

Applicant(s)/Patent under  
Reexamination

HOSOYA ET AL.

Art Unit

3747

**SEARCHED**

Class	Subclass	Date	Examiner
123	697	6/16/2005	HHH
73	23.32	6/16/2005	HHH
204	406	6/16/2005	HHH
204	425	6/16/2005	HHH
60	274	6/16/2005	HHH
60	276	6/16/2005	HHH
60	277	6/16/2005	HHH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	6/16/2005	HHH